

15992 U.S. PTO  
10/02/03  
12/19/01

PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10027639	FILING DATE 12/19/2001	CLASS <del>382</del>	SUBCLASS 462.250	GAU <del>3624</del>	EXAMINER SANDEKS, A.
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255

2876

\*\*CONTINUING DATA VERIFIED:

None

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\*\* FOREIGN APPLICATIONS VERIFIED:  
REPUBLIC OF KOREA 2001-2569 01/17/2001

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
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Foreign priority claimed	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO 9903-44
35 USC 119 conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	
Verified and Acknowledged Examiners's initials <i>u</i>		

TITLE : Method and apparatus for detecting defective markings on a semiconductor product

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
Assistant Examiner		DRAWING	
ISSUE FEE		Sheets Drwg.	Figs. Drwg.
Amount Due	Date Paid	Print Fig.	
PRIMARY EXAMINER		Applicati n Examiner	
PREPARED FOR ISSUE			
<input type="checkbox"/> TERMINAL DISCLAIMER		WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.	

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